

8N70

Power MOSFET

8A, 700V N-CHANNEL
POWER MOSFET

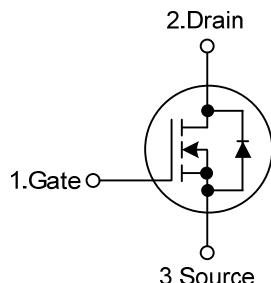
■ DESCRIPTION

The UTC **8N70** is an N-channel power MOSFET using UTC's advanced technology to provide the customers with minimum on-state resistance, superior switching performance and withstand high energy pulse in the avalanche and commutation mode.

■ FEATURES

- * $R_{DS(ON)} = 1.4\Omega$ @ $V_{GS}=10V$, $I_D=4A$
- * High switching speed
- * Low Gate Charge(typical 32nC)
- * Low C_{RSS} (typical 13.7pF)

■ SYMBOL



■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
8N70L-TA3-T	8N70G-TA3-T	TO-220	G	D	S	Tube
8N70L-TF3-T	8N70G-TF3-T	TO-220F	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

8N70L-TA3-T 	(1)T: Tube (2) TA3: TO-220, TF3: TO-220F (3) G: Halogen Free, L: Lead Free
-----------------	--

■ ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	700	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous $T_c=25^\circ\text{C}$	I_D	8	A
			4.8	A
	Pulsed (Note 4)	I_{DM}	32	A
Avalanche Current	Repetitive (Note 2)	I_{AR}	8	A
	Repetitive (Note 3)	I_{AS}	8	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	266	mJ
	Repetitive (Note 2)	E_{AR}	11.6	mJ
Power Dissipation ($T_c=25^\circ\text{C}$)		P_D	147	W
TO-220			40	
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55~+150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature

3. L = 7.74mH, $I_{AS} = 8\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$

4. Limited by maximum junction temperature

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient		θ_{JA}	62.5	°C/W
Junction to Case	TO-220	θ_{JC}	0.85	°C/W
	TO-220F		3.1	

Note: Surface mounted on FR4 board $t \leq 10\text{sec}$

■ ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	700			V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=700\text{V}$, $V_{GS}=0\text{V}$			1	μA
Gate-Source Leakage Current	Forward	I_{GSS}	$V_{GS}=+30\text{V}$, $V_{DS}=0\text{V}$			+10 nA
	Reverse		$V_{GS}=-30\text{V}$, $V_{DS}=0\text{V}$			-10 nA
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(\text{TH})}$	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	2.0		4.0	V
Static Drain-Source On-State Resistance	$R_{DS(\text{ON})}$	$V_{GS}=10\text{V}$, $I_D=4\text{A}$		1.2	1.4	Ω
DYNAMIC PARAMETERS						
Input Capacitance	C_{ISS}	$V_{GS}=0\text{V}$, $V_{DS}=25\text{V}$, $f=1.0\text{MHz}$		2006		pF
Output Capacitance	C_{OSS}			148		pF
Reverse Transfer Capacitance	C_{RSS}			13.7		pF

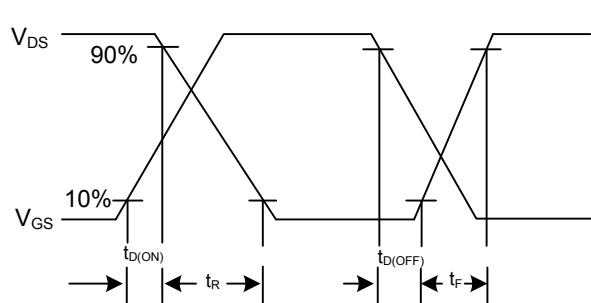
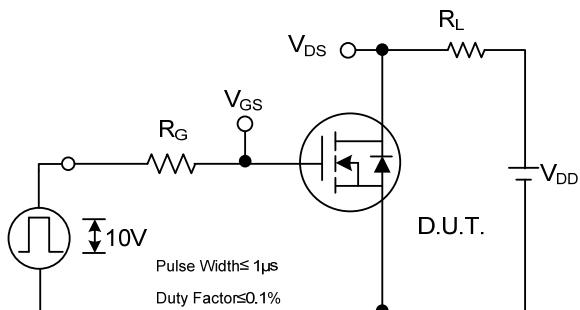
■ ELECTRICAL CHARACTERISTICS(Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SWITCHING PARAMETERS						
Total Gate Charge	Q_G	$V_{GS}=10V, V_{DS}=560V, I_D=8A$	32			nC
Gate to Source Charge	Q_{GS}	(Note 1, 2)	9			nC
Gate to Drain Charge	Q_{GD}		8			nC
Turn-ON Delay Time	$t_{D(ON)}$		23			ns
Rise Time	t_R	$V_{DD}=300V, I_D=10A, R_G=25\Omega$	69			ns
Turn-OFF Delay Time	$t_{D(OFF)}$	$V_{GS}=10V$ (Note 1, 2)	144			ns
Fall-Time	t_F		77			ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I_S	Integral reverse diode in the		8		A
Maximum Body-Diode Pulsed Current	I_{SM}	MOSFET		32		A
Drain-Source Diode Forward Voltage	V_{SD}	$I_S=8A, V_{GS}=0V$		1.4		V
Body Diode Reverse Recovery Time	t_{rr}	$I_S=8A, V_{GS}=0V, dI_F/dt=100A/\mu s$	420			ns
Body Diode Reverse Recovery Charge	Q_{RR}		4.2			μC

Notes: 1. Essentially independent of operating temperature

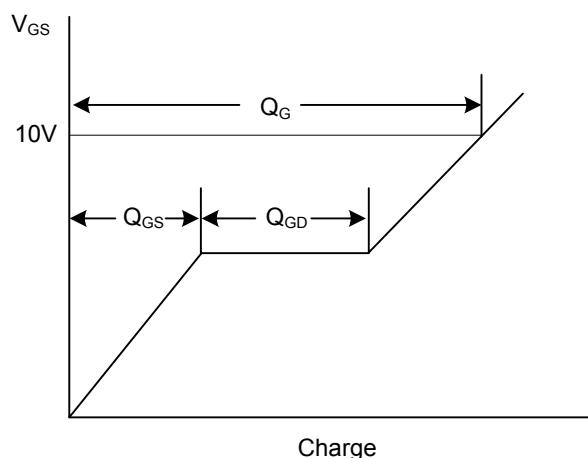
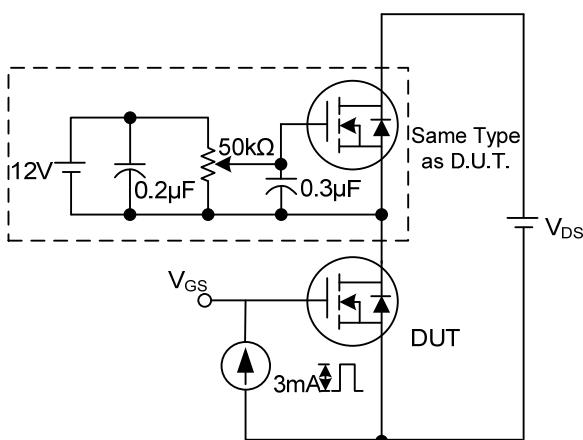
2. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

■ TEST CIRCUITS AND WAVEFORMS



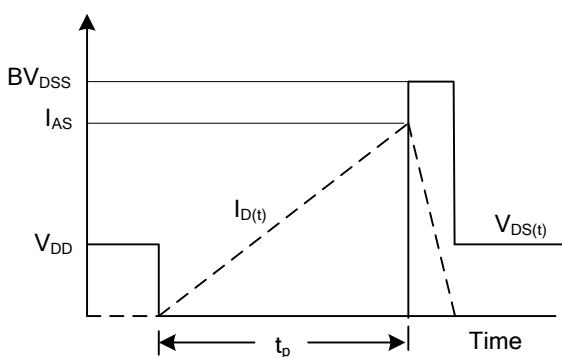
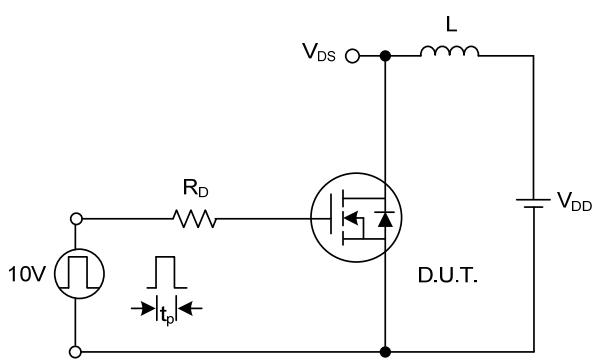
Switching Test Circuit

Switching Waveforms



Gate Charge Test Circuit

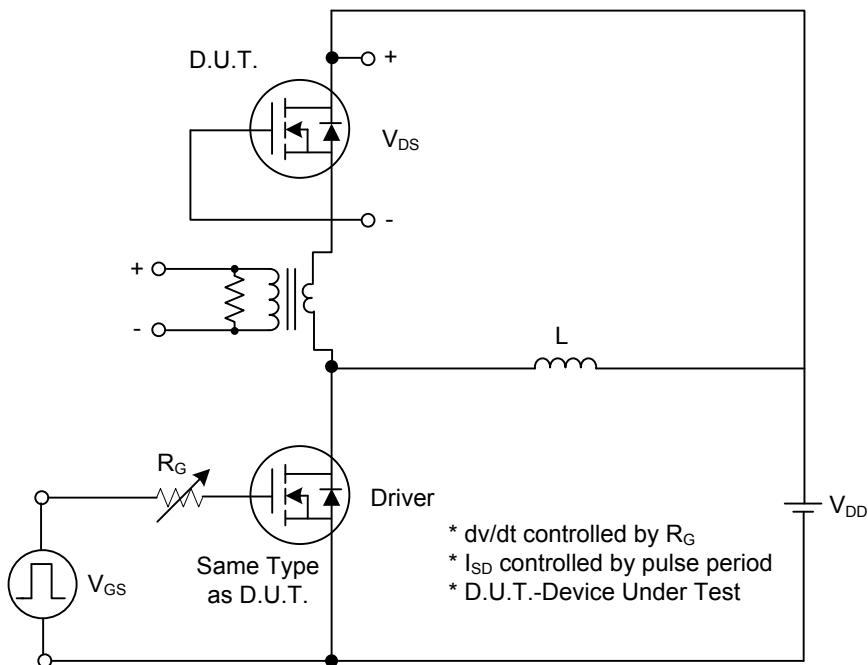
Gate Charge Waveform



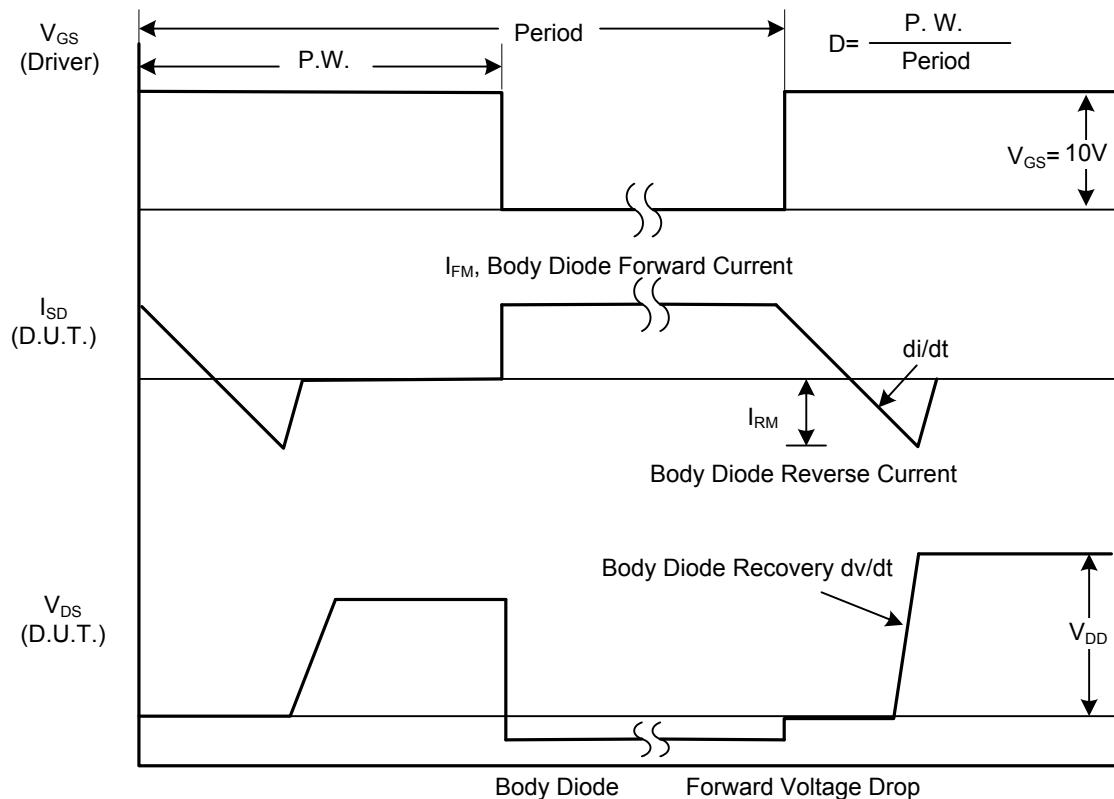
Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

■ TEST CIRCUITS AND WAVEFORMS(Cont.)

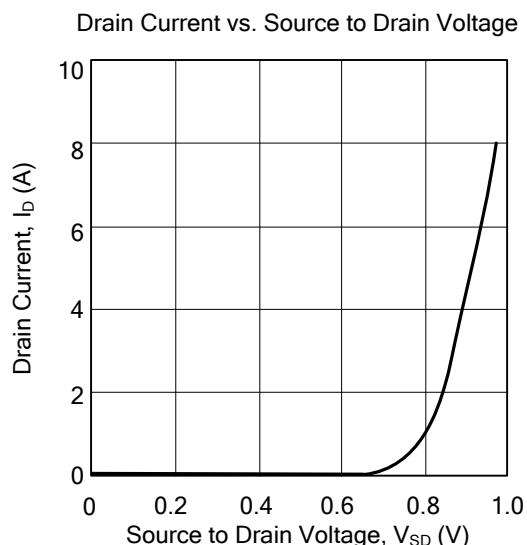
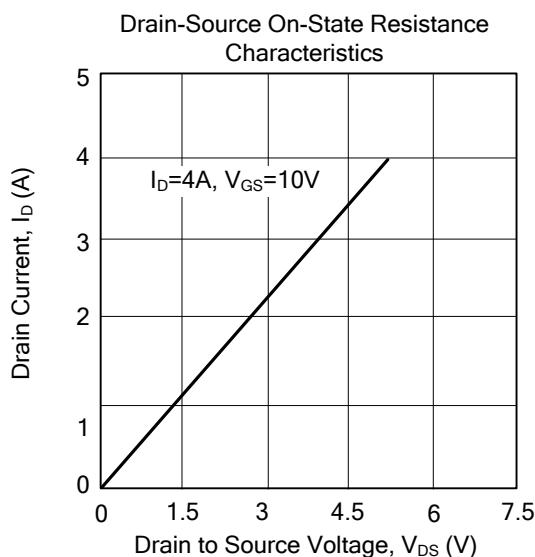
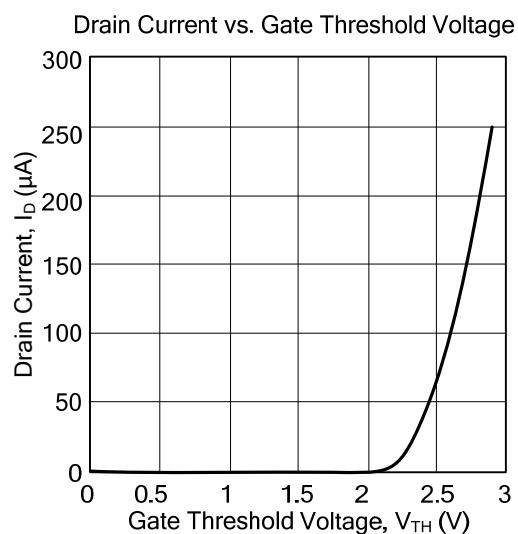
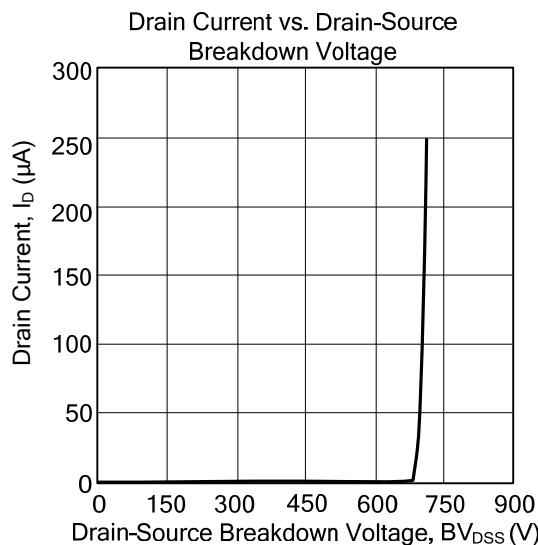


Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

■ TYPICAL CHARACTERISTICS



UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. The information presented in this document does not form part of any quotation or contract, is believed to be accurate and reliable and may be changed without notice.